# UNITED STATES PATENT AND TRADEMARK OFFICE CERTIFICATE OF CORRECTION

PATENT NO.

: 6,955,940 B2

Page 1 of 3

DATED

: October 18, 2005

INVENTOR(S) : Kristy A. Campbell et al.

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

## Title page,

Item [56], References Cited, FOREIGN PATENT DOCUMENTS,

"WO 97/488032" should read -- WO 97/48032 --.

OTHER PUBLICATIONS,

"Hirose, et al, "Polanty-dependent memory switching and behavior of Ag dendrite in Ag-photodoped amorphous  $As_2S_3$  films", Journal of Applied Physics, vol. 47, No. 6, Jun. 1976, pps 2767-2772."

should read

- -- Hirose, et al., "Polarity-dependent memory switching and behavior of Ag dendrite in Ag-photodoped amorphous As<sub>2</sub>S<sub>3</sub> films", Journal of Applied Physics. Vol. 47. No. 6. Jun. 1976. pps 2767-2772. --.
- "Kluge, et al, "Silver photodiffusion in amorphous Ge,Se<sub>co</sub>", Journal of Non-Crystalline Solids 124 (1990) pps 186-193." should read
- -- Kluge, et al., "Silver photodiffusion in amorphous Ge<sub>x</sub>Se<sub>100-x</sub>", Journal of Non-Crystalline Solids 124 (1990) pps 186-193. --;
- "Shimakawa et al., Photoinduced effects and metastability in amorphous semiconductors and insulators, 44 Advances n Physics No. 6, 475-588 (Taylor & Francis 1995)." should read
- -- Shimakawa et al., Photoinduced effects and metastability in amorphous semiconductors and insulators, 44 Advances in Physics No. 6, 475-588 (Taylor & Francis 1995). --;
- "Drusedau, T.P.; Panckow, A.N.; Klabunda, F., The hydrogenated amorphous silicon/nanodisperse metal (SIMAL) system--Films of unique electronic properties, J. Non-Cryst. Solids 198-200 (1996) 829-832." should read
- -- Drusedau, T.P.; Panckow, A.N.; Klabunde, F., The hydrogenated amorphous silicon/nanodisperse metal (SIMAL) system--Films of unique electronic properties, J. Non-Cryst. Solids 198-200 (1996) 829-832. --;
- "Guin, J.-P.; Rouxel, T.; Keryvin, V.; Sangleboeuf, J.-C.; Serre, I.; Lucal, J., Identation creep of Ge-Se chalcogenide glasses below Tg. elastic recovery and non-Newtonian flow, J. Non-Cryst. Solids 298 (2002) 260-269." should read
- -- Guin, J.-P.; Rouxel, T.; Keryvin, V.; Sangleboeuf, J.-C.; Serre, I.; Lucas, J., Indentation creep of Ge-Se chalcogenide glasses below Tg: elastic recovery and non-Newtonian flow, J. Non-Cryst. Solids 298 (2002) 260-269. --;

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## Title page (cont'd),

"Guin, J.-P.; Rouxel, T.; Sangelboeuf, J.-C.; Melscoel, I.; Lucas, J., Hardness, toughness, and scratchability of germanium-selenium chalcogenide glasses, J. Am. Ceram. Soc. 85 (2002) 1545-52." should read

- -- Guin, J.-P.; Rouxel, T.; Sangelboeuf, J.-C.; Melscoet, I.; Lucas, J., Hardness, toughness, and scratchability of germanium-selenium chalcogenide glasses, J. Am. Ceram. Soc. 85 (2002) 1545-52. --.
- "Cahen, D.; Gilet, J.-M.; Schmitz, C.; Chernyak, L.; Gartsman, K.; Jakubowicz, A., Room-Temperature, electric field induced creation of stable devices in CulnSe2 Crystals, Science 258 (1992) 271-274." should read
- -- Cahen, D.; Gilet, J.-M.; Schmitz, C.; Chernyak, L.; Gartsman, K.; Jakubowicz, A., Room-temperature, electric field induced creation of stable devices in CuInSe2 crystals, Science 258 (1992) 271-274. --;
- "Kotkata, M.F.; Afif, M.A.; Labib, H.H.; Hegab, N.A.; Abdel-Aziz, M.M., Memory switching in amorphous GeSeTl chalcogenide semiconductor films, Thin Solid Films 240 (1994) 143-146."

should read

- -- Kotkata, M.F.; Afifi, M.A.; Labib, H.H.; Hegab, N.A.; Abdel-Aziz, M.M., Memory switching in amorphous GeSeTl chalcogenide semiconductor films, Thin Solid Films 240 (1994) 143-146. --;
- "Tranchant, S.; Peytavin, S.; Ribes, M.; Flank, A.M.; Dexpert, H.; Legarde, J.P., Silver chalcogenide glasses Ag-Ge-Se: Ionic conduction and exafs structural investigation, Transport-structure relations in fast ion and mixed conductors Proceedings of the 6th Riso International Symposium. Sep. 9-13, 1985." should read
- -- Tranchant, S.; Peytavin, S.; Ribes, M.; Flank, A.M.; Dexpert, H.; Lagarde, J.P., Silver chalcogenide glasses Ag-Ge-Se: Ionic conduction and EXAFS structural investigation, Transport-structure relations in fast ion and mixed conductors. Proceedings of the 6th Riso International Symposium. Sep. 9-13, 1985. --.
- "Rose, M.J.; Snell, A.J.; Lecomber, P.G.; Hajto, J.; Fitzgerald, A.G.; Owen, A.E., Aspects of non-volatility in a -Si:H memory devices, Mat. Res. Soc. Symp. Proc. V 258, 1992, 1075-1080." should read
- -- Rose, M.J.; Snell, A.J.; Lecomber, P.G.; Hajto, J.; Fitzgerald, A.G.; Owen, A.E., Aspects of non-volatility in metal/a -Si:H/metal memory devices, Mat. Res. Soc. Symp. Proc. V 258, 1992, 1075-1080. --.

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# Title page (cont'd),

Item [74], Attorney, Agent, or Firm, "Dickstein Shaprio Morin & Oshinsky LLP" should read -- Dickstein Shapiro Morin & Oshinsky LLP --.

Item [57], ABSTRACT,

Line 10, "to and HNO<sub>3</sub>" should read -- to an HNO<sub>3</sub> --.

Line 45, "example only, example" should read -- example only, --.

Line 52, "comprises and oxide" should read -- comprises an oxide --.

### Column 9,

Line 17, "atomosphere" should read -- atmosphere --.

Signed and Sealed this

Twenty-first Day of March, 2006

JON W. DUDAS Director of the United States Patent and Trademark Office